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Title: Stripline Method for EM-Material Characterization

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20/2

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Abstract: Analysis of stripline for thin film characterization has been performed using cavity model based equivalent circuit. Historical review of previous methods and the result based analysis of the proposed method is the main emphasis of this report. The proposed method is also compared with experimental one and found that the method is appropriate for the analysis of stripline. The effect of various parameters of stripline on resonance frequency is also studied and these effects can play a major role in the design of stripline for EM material characterization of thin films.